Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,719	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2624	

	SEARCHED			
Class	Subclass	Date	Examiner	
358	1.15, 402, 440	9/27/2005	TDL	
379	100.01	9/27/2005	TDL	
379	100.08	9/27/2005	TDL	
379	100.13	9/27/2005	TDL	
379	100.17	9/27/2005	TDL	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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